

<b>Notice of References Cited</b>	Application/Control No. 10/707,373		Applicant(s)/Patent Under Reexamination HUISMAN ET AL.	
	Examiner Cynthia Britt		Art Unit 2138	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,278,956 B1	08-2001	Leroux et al.	702/117
*	B	US-6,694,454 B1	02-2004	Stanley, Kevin W.	714/30
*	C	US-4,630,270 A	12-1986	Petit et al.	714/45
*	D	US-2003/0131294 A1	07-2003	Motika et al.	714/718
*	E	US-6,553,524 B1	04-2003	Das, Subrangshu Kumar	714/726
*	F	US-6,016,564 A	01-2000	Hosokawa, Toshinori	714/726
*	G	US-5,598,421 A	01-1997	Tran et al.	714/726
*	H	US-6,442,720 B1	08-2002	Koprowski et al.	714/726
*	I	US-5,663,967 A	09-1997	Lindberg et al.	714/737
*	J	US-2002/0188903 A1	12-2002	Chu et al.	714/738
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 1130410 A2	09-2006	EPO	TANAKA et al.	G01R 31/3185
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Diagnosing Scan Chain Faults" by Kundu, S. This paper appears in: IEEE Transactions on Very Large Scale Integration (VLSI) Systems, Publication Date: Dec 1994 Volume: 2, Issue: 4 On page(s): 512-516 ISSN: 1063-8210 INSPEC Accession Number: 4839256
	V	"Scan Chain Diagnosis Using IDDQ Current Measurement" by Hirase et al. This paper appears in: Eighth Asian Test Symposium, 1999. (ATS '99) Proceedings. Publication Date: 1999 On page(s): 153-157 ISBN: 0-7695-0315-2 INSPEC Accession Number: 6544163
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.